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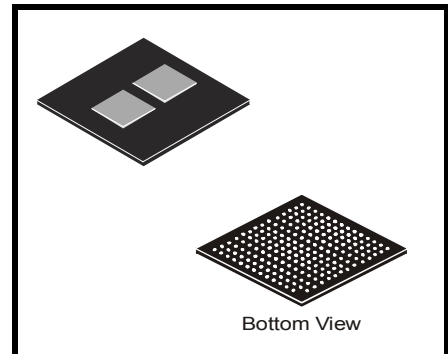


SiPHY™ OC-48/STM-16 SONET/SDH TRANSCEIVER

Features

Complete, low-power, high-speed, SONET/SDH transceiver with integrated limiting amp, CDR, CMU, and MUX/DEMUX

- Data rates supported: OC-48/STM-16 through 2.7 Gbps FEC
- Low-power operation 1.2 W (typ)
- DSPLL™ based clock multiplier unit w/ selectable loop filter bandwidths
- Integrated limiting amplifier
- Loss-of-signal (LOS) alarm
- Diagnostic and line loopbacks
- SONET-compliant loop timed operation
- Programmable slicing level and sample phase adjustment
- LVDS/LVPECL compatible interface
- Single supply 1.8 V operation
- 15 x 15 mm BGA package



Ordering Information:

See page 35.

Applications

- SONET/SDH transmission systems
- Optical transceiver modules
- SONET/SDH test equipment

Description

The Si5100 is a complete low-power transceiver for high-speed serial communication systems operating between OC-48 and 2.7 Gbps. The receive path consists of a fully-integrated limiting amplifier, clock and data recovery unit (CDR), and 1:16 deserializer. The transmit path combines a low-jitter clock multiplier unit (CMU) with a 16:1 serializer. The CMU uses Silicon Laboratories' DSPLL technology to provide superior jitter performance while reducing design complexity by eliminating external loop filter components. To simplify BER optimization in long-haul applications, programmable slicing and sample phase adjustment are supported. The Si5100 operates from a single 1.8 V supply over the industrial temperature range (-20 to 85 °C).

Functional Block Diagram

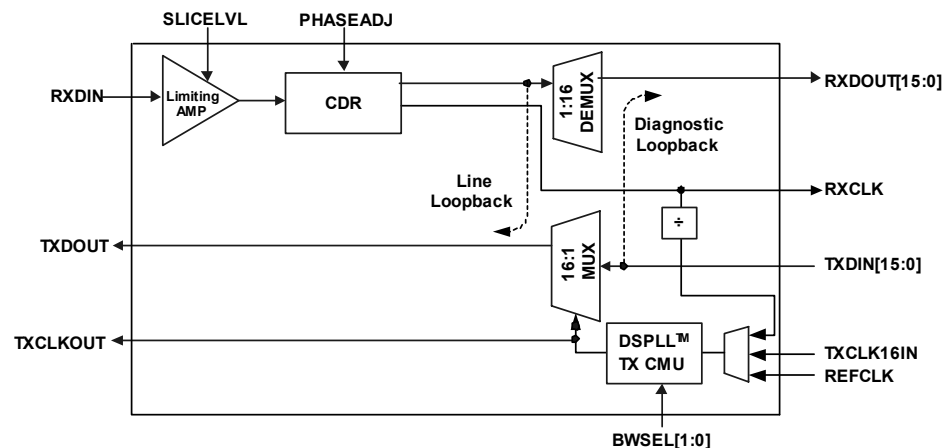
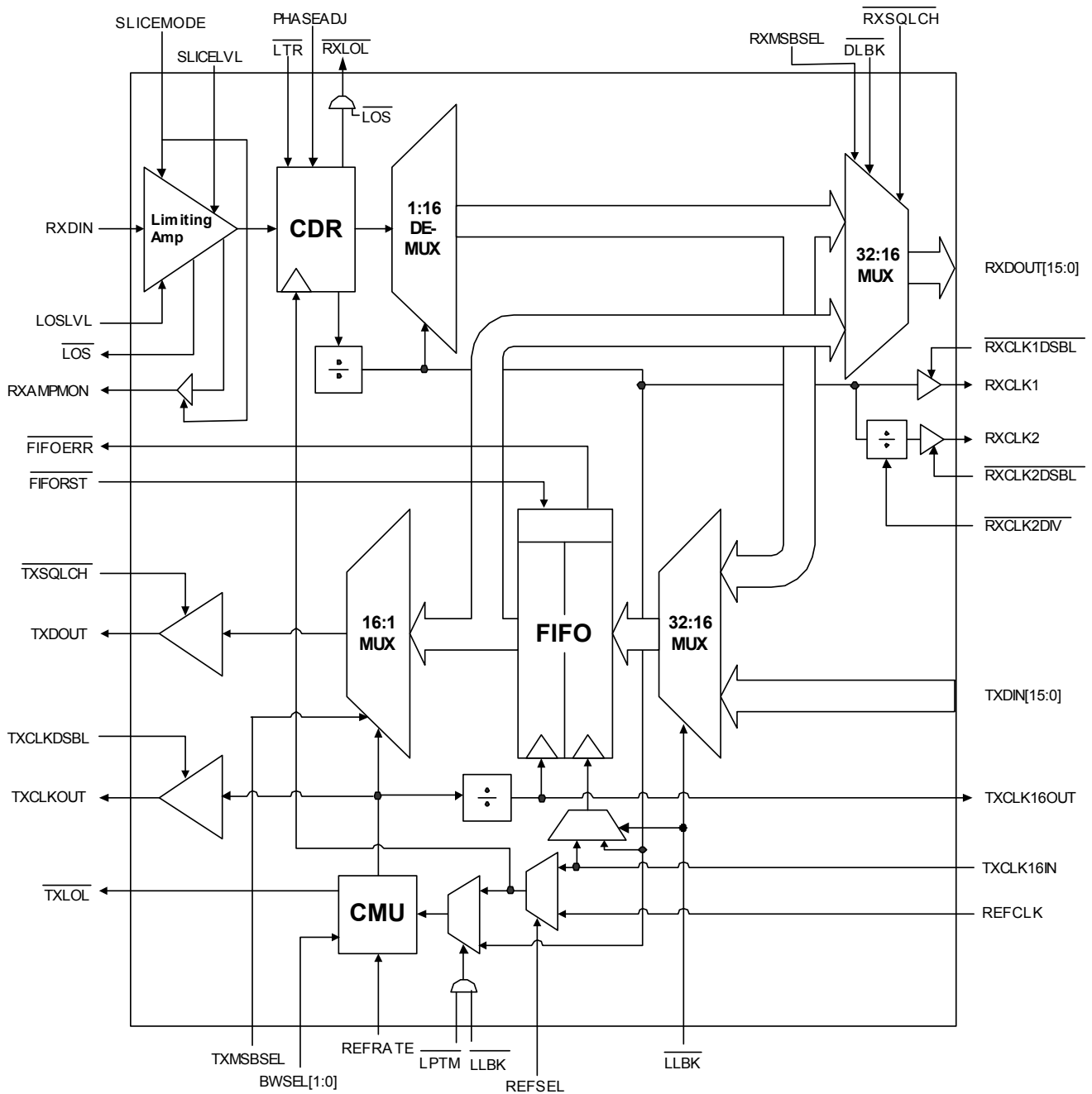


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1. Si5100 Detailed Block Diagram



2. Electrical Specifications

Table 1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min*	Typ	Max*	Unit
Ambient Temperature	T_A		-20	25	85	°C
LVTTL Output Supply Voltage	V_{DDIO}		1.71	—	3.47	V
Si5100 Supply Voltage	VDD		1.71	1.8	1.89	V

***Note:** All minimum and maximum specifications are guaranteed and apply across the recommended operating conditions. Typical values apply at nominal supply voltages and an operating temperature of 25°C unless otherwise stated.

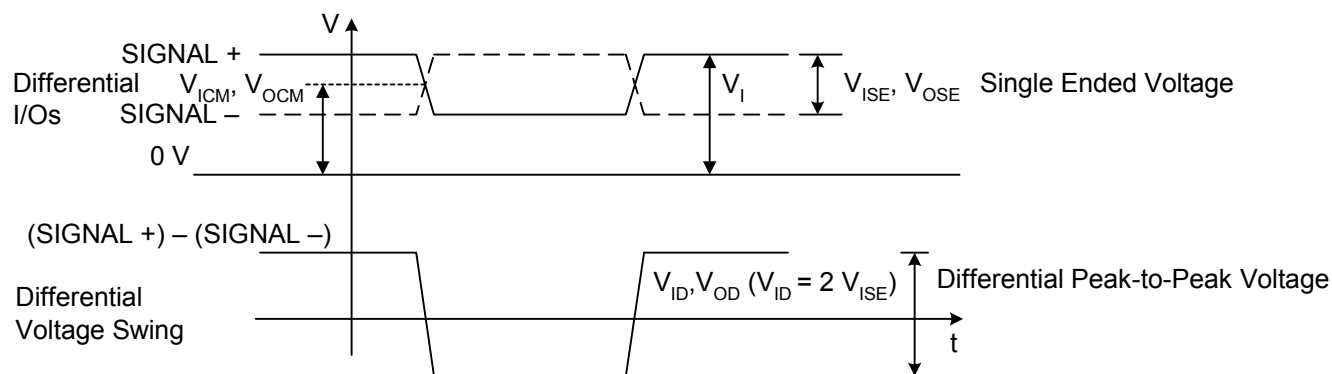


Figure 1. Differential Voltage Measurement
(RXDIN, RXDOUT, RXCLK1, RXCLK2, TXDIN, TXDOUT, TXCLKOUT, TXCLK16OUT, TXCLK16IN)

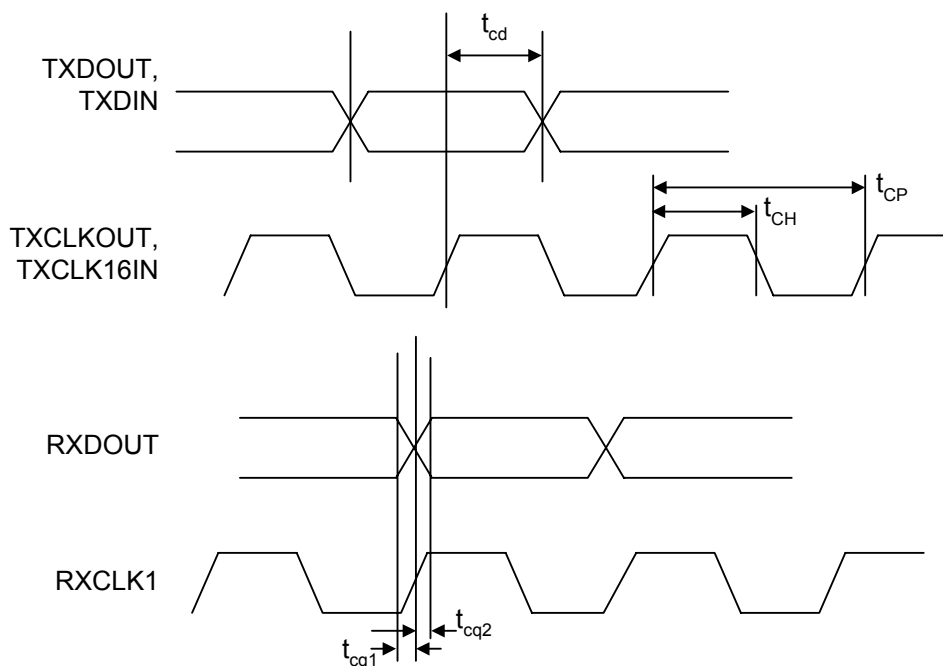


Figure 2. Data to Clock Delay

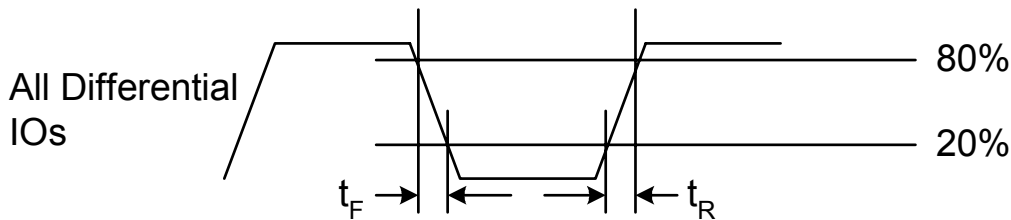


Figure 3. Rise/Fall Time Measurement

Table 2. DC Characteristics

($V_{DD} = 1.8\text{ V} \pm 5\%$, $T_A = -20\text{ to }85\text{ }^\circ\text{C}$)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply Current	I_{DD}	Full Duplex Line/Diagnostic Loopback	—	680 760	760 830	mA
Power Dissipation	P_D	Full Duplex Line/Diagnostic Loopback	—	1.2 1.4	1.4 1.6	W
Voltage Reference (VREF)	V_{REF}	VREF driving 10 k Ω load	1.21	1.25	1.29	V
Common Mode Input Voltage (RXDIN)	V_{ICM}		0.4	0.5	0.6	V
Differential Input Voltage Swing (RXDIN) (@ Bit Error Rate of 10^{-12})	V_{ID}	Figure 1	30	—	2000 ¹	mV _{PPD}
Common Mode Output Voltage (TXDOUT, TXCLKOUT)	V_{OCM}		0.7	0.9	1.1	V
Differential Output Voltage Swing (TXDOUT, TXCLKOUT), Differential PK-PK	V_{OD}	Figure 1	1000	1200	1400	mV _{PPD}
LVPECL Input Voltage Level (REFCLK)	V_I		0.8	—	2.5	V
LVPECL Input Voltage Swing, Differential PK-PK (REFCLK)	V_{ID}	Figure 1	250	—	2400	mV _{PPD}
LVDS Input Voltage Level (TXDIN, TXCLK16IN)	V_I		.8	1.2	2.4	V
LVDS Input Voltage, Differential PK-PK (TXDIN, TXCLK16IN)	V_{ID}		200 ²	—	—	mV _{PPD}
LVDS Output Voltage Level (RXDOUT, RXCLK1, RXCLK2, TXCLK16OUT)	V_O	100 Ω Load Line-to-Line	0.925	—	1.475	V
LVDS Output Voltage, Differential PK-PK (RXDOUT, RXCLK1, RXCLK2, TXCLK16OUT)	V_{OD}	100 Ω Load Line-to-Line, Figure 1	550 ²	650	800	mV _{PPD}

Notes:

1. Voltage on either RXDIN+ or RXDIN– should not exceed 1000 mV_{PP} (single-ended).
2. LVDS differential voltages are for a 16-bit parallel data operation of the multiplexer/demultiplexer (MODE 16 = 1).

Table 2. DC Characteristics (Continued) $(V_{DD} = 1.8\text{ V} \pm 5\%, T_A = -20\text{ to }85\text{ }^\circ\text{C})$

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
LVDS Common Mode Output Voltage (RXDOUT, RXCLK1, RXCLK2, TXCLK16OUT)	V_{CM}		1.125	1.2	1.275	V
Input Impedance (RXDIN)	R_{IN}	Each input to common mode	42	50	58	Ω
LVDS and LVPECL Input Impedance (TXDIN, TXCLK16IN, REFCLK)	R_{IN}	Each input to common mode	45	55	65	Ω
CML Output Impedance (TXDOUT, TXCLKOUT)	R_{OUT}	Each output to common mode	45	55	65	Ω
LVDS Output Impedance (RXDOUT, RXCLK1, RXCLK2, TXCLK16OUT)	R_{OUT}	Each output to common mode	45	55	65	Ω
Output Current Short to GND (RXDOUT, RXCLK1, RXCLK2, TXCLK16OUT)	$I_{SC(-)}$		—	12	40	mA
Output Current Short to V_{DD} (RXDOUT, RXCLK1, RXCLK2, TXCLK16OUT)	$I_{SC(+)}$		-8	-6	—	mA
LVTTTL Input Voltage Low	V_{IL2}	$V_{DDIO} = 1.8\text{--}3.3\text{ V}$	-0.3	—	$0.35 V_{DDIO}$	V
LVTTTL Input Voltage High	V_{IH2}	$V_{DDIO} = 1.8\text{--}3.3\text{ V}$	$0.65 V_{DDIO}$	—	$V_{DDIO} + 0.3$	V
LVTTTL Input Impedance	R_{IN}		10	—	—	k Ω
LVTTTL Output Voltage Low ($I_{OUT} = 2\text{ mA}$)	V_{OL2}	$V_{DDIO} = 1.8\text{--}3.3\text{ V}$	—	—	0.4	V
LVTTTL Output Voltage High ($I_{OUT} = 2\text{ mA}$)	V_{OH2}	$V_{DDIO} = 1.8\text{--}3.3\text{ V}$	$V_{DDIO} - 0.45$	—	—	V
RXAMPMON Output Impedance	R_{OUT}		4	6	8	k Ω
LOS/SLICELVL/PHASEADJ Input Impedance	R_{IN}		100	—	—	k Ω

Notes:

1. Voltage on either RXDIN+ or RXDIN- should not exceed 1000 mV_{pp} (single-ended).
2. LVDS differential voltages are for a 16-bit parallel data operation of the multiplexer/demultiplexer (MODE 16 = 1).



Table 3. AC Characteristics (RXDIN, RXDOUT, RXCLK1, RXCLK2)

($V_{DD} = 1.8\text{ V} \pm 5\%$, $T_A = -20\text{ to }85\text{ }^\circ\text{C}$)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Data Rate (RXDIN)			2.41	—	2.7	Gbps
Output Clock Frequency (RXCLK1)	f_{clkout}	MODE16 = 1 MODE16 = 0	— —	155 622	167 675	MHz
Output Clock Frequency (RXCLK2)	f_{clkout}	MODE16 = 1, RXCLK2DIV = 1 MODE16 = 1, RXCLK2DIV = 0 MODE16 = 0, RXCLK2DIV = 1 MODE16 = 0, RXCLK2DIV = 0	— — — —	155 38.9 622 155	169 42.2 675 169	MHz
Duty Cycle (RXCLK1, RXCLK2)		tch/tcp, Figure 2	45	—	55	%
Output Rise and Fall Times (RXCLK1, RXCLK2, RXDOUT)	t_R, t_F	Figure 3	100	175	250	ps
Data Invalid Prior to RXCLK1	t_{cq1}	Figure 2	—	—	200	ps
Data Invalid After RXCLK1	t_{cq2}	Figure 2	—	—	200	ps
Input Return Loss (RXDIN)	S_{11}	$\leq 1.25\text{ GHz}$ 2.5 GHz	— —	-12 -10	— —	dB dB
LOS Threshold ¹ , SLICEMODE = 0	V_{LOS}	LOSLVL = 0–350 mV	0	—	250	mV
LOS Threshold Error ¹ , SLICEMODE = 0			—	—	± 30	%
LOS Threshold ² , SLICEMODE = 1	V_{LOS}	LOSLVL = 0–500 mV	0	—	60	mV
LOS Threshold Error ² , SLICEMODE = 1 RXDIN > 30 mV			—	—	± 50	%
Slice Voltage ³ , SLICEMODE = 0	V_{LEVEL}	SLICELVL = 350 mV SLICELVL = 650 mV	— —	-50 40	— —	mV mV
Slice Voltage as Percentage of Differential Input Voltage Swing (RXDIN), SLICEMODE = 1 ⁴	V_{LEVEL}	SLICELVL = 250 mV SLICELVL = 750 mV	— —	-25 18	— —	% %
Sample Phase ⁵		PHASEADJ = 200 mV PHASEADJ = 800 mV	— —	-25 25	— —	ps ps
RXAMPMON Voltage Range		RXDIN = 0–1000 mV _{PPD}	0	—	550	mV
RXAMPMON Voltage Error			—	—	± 50	%

Notes:

1. See Figure 4 on page 16.
2. See Figure 5 on page 17.
3. See Figure 6 on page 17.
4. See Figure 7 on page 18.
5. See Figure 8 on page 18.

Table 4. AC Characteristics (TXCLK16OUT, TXCLK16IN, TXCLKOUT, TXDIN, TXDOUT) $(V_{DD} = 1.8\text{ V} \pm 5\%, T_A = -20\text{ to } 85\text{ }^\circ\text{C})$

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
TXCLKOUT Frequency	f_{clkout}		2.41	—	2.7	GHz
TXCLKOUT Duty Cycle		tch/tcp, Figure 2	40	50	60	%
Output Rise Time (TXCLKOUT, TXDOUT)	t_R	Figure 3	—	50	75	ps
Output Fall Time (TXCLKOUT, TXDOUT)	t_F	Figure 3	—	50	75	ps
TXCLKOUT to TXDOUT Delay	t_{CD}	Figure 2	-42	—	-22	ps
Output Return Loss		100 kHz–2.5 GHz 2.5–4.0 GHz	— —	-12 -10	— —	dB dB
TXCLK16OUT Frequency	f_{CLKOUT}	MODE16 = 1 MODE16 = 0	— —	155 622	169 675	MHz
TXCLK16OUT Duty Cycle		tch/tcp, Figure 2	40	—	60	%
TXCLK16OUT Rise & Fall Times	t_R, t_F		100	175	250	ps
TXDIN Setup to TXCLK16IN	t_{DSIN}		—	—	300	ps
TXDIN Hold from TXCLK16IN	t_{DHIN}		—	—	300	ps
TXCLK16IN Frequency	f_{CLKIN}	MODE16 = 1 MODE16 = 0	— —	155 622	169 675	MHz
TXCLK16IN Duty Cycle		tch/tcp, Figure 2	40	—	60	%
TXCLK16IN Rise & Fall Times	t_R, t_F		100	—	300	ps

Table 5. AC Characteristics (Receiver PLL)¹

($V_{DD} = 1.8\text{ V} \pm 5\%$, $T_A = -20\text{ to }85\text{ }^\circ\text{C}$)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Jitter Tolerance (RXDIN = 100 mV _{PPD} , PRBS31) ²	J _{TOL(PP)}	f = 10 – 600 Hz	15 ²	—	—	UI _{PP}
		f = 0.6 – 6 kHz	15 ²	—	—	UI _{PP}
		f = 6 – 100 kHz	9 ²	—	—	UI _{PP}
		f = 100 kHz–1 MHz	0.4	—	—	UI _{PP}
		f = 1–20 MHz	0.3	—	—	UI _{PP}
Acquisition Time	T _{AQ}		—	—	2	ms
Input Reference Clock Frequency (REFSEL = 1)	RC _{FREQ}	REFRATE = 1	—	155	169	MHz
		REFRATE = 0	—	78	84.4	MHz
Reference Clock Duty Cycle	RC _{DUTY}		40	50	60	%
Reference Clock Frequency Tolerance	RC _{TOL}		-100	—	100	ppm
Frequency Difference at which Receive PLL goes out of Lock (REFCLK compared to the divided down VCO clock)	$\overline{\text{LOL}}$		610	732	860	ppm
Frequency Difference at which Receive PLL goes into Lock (REFCLK compared to the divided down VCO clock)	LOCK		—	366	240	ppm

Notes:

1. Bellcore specifications: GR-253-CORE, Issue 3, September 2000.
2. Instrument limited.

Table 6. AC Characteristics (Transmitter Clock Multiplier)¹ $(V_{DD} = 1.8\text{ V} \pm 5\%, T_A = -20\text{ to }85\text{ }^\circ\text{C})$

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Jitter Transfer Bandwidth (OC-48: 2.48832 Gbps)	J_{BW}	BWSEL[1:0] = 00	—	—	12	kHz
		BWSEL[1:0] = 01	—	—	50	kHz
		BWSEL[1:0] = 10	—	—	120	kHz
		BWSEL[1:0] = 11	—	—	200	kHz
Jitter Transfer Bandwidth (FEC: 2.66667 Gbps)	J_{BW}	BWSEL[1:0] = 00	—	—	12	kHz
		BWSEL[1:0] = 01	—	—	50	kHz
		BWSEL[1:0] = 10	—	—	120	kHz
		BWSEL[1:0] = 11	—	—	200	kHz
Jitter Transfer Peaking			—	0.05	0.1	dB
Acquisition Time	T_{AQ}	Valid REFCLK	—	—	20	ms
Input Reference Clock Frequency	RC_{FREQ}	REFRATE = 1	—	155	169	MHz
		REFRATE = 0	—	78	84.4	
Input Reference Clock Duty Cycle	RC_{DUTY}		40	—	60	%
Input Reference Clock Frequency Tolerance	RC_{TOL}		-100	—	100	ppm
Random rms Jitter Generation, TXCLKOUT (PRBS 31) ²	$J_{GEN(rms)}$	BWSEL[1:0] = 00	—	2.5	3.4	mUI_{rms}
		BWSEL[1:0] = 01	—	2.0	2.4	mUI_{rms}
		BWSEL[1:0] = 10	—	1.7	2.1	mUI_{rms}
		BWSEL[1:0] = 11	—	1.7	1.8	mUI_{rms}
Total Peak-to-Peak Jitter Generation, TXCLKOUT, TXDOUT (PRBS 31) ²	$J_{GEN(pp)}$	BWSEL[1:0] = 00	—	25.5	34	mUI_{pp}
		BWSEL[1:0] = 01	—	24.0	33	mUI_{pp}
		BWSEL[1:0] = 10	—	22.0	27	mUI_{pp}
		BWSEL[1:0] = 11	—	22.0	26	mUI_{pp}

Notes:

1. Bellcore specifications: GR-253-CORE, Issue 3, September 2000.
2. Full duplex; REFCLK = 155 MHz.



Table 7. Absolute Maximum Ratings

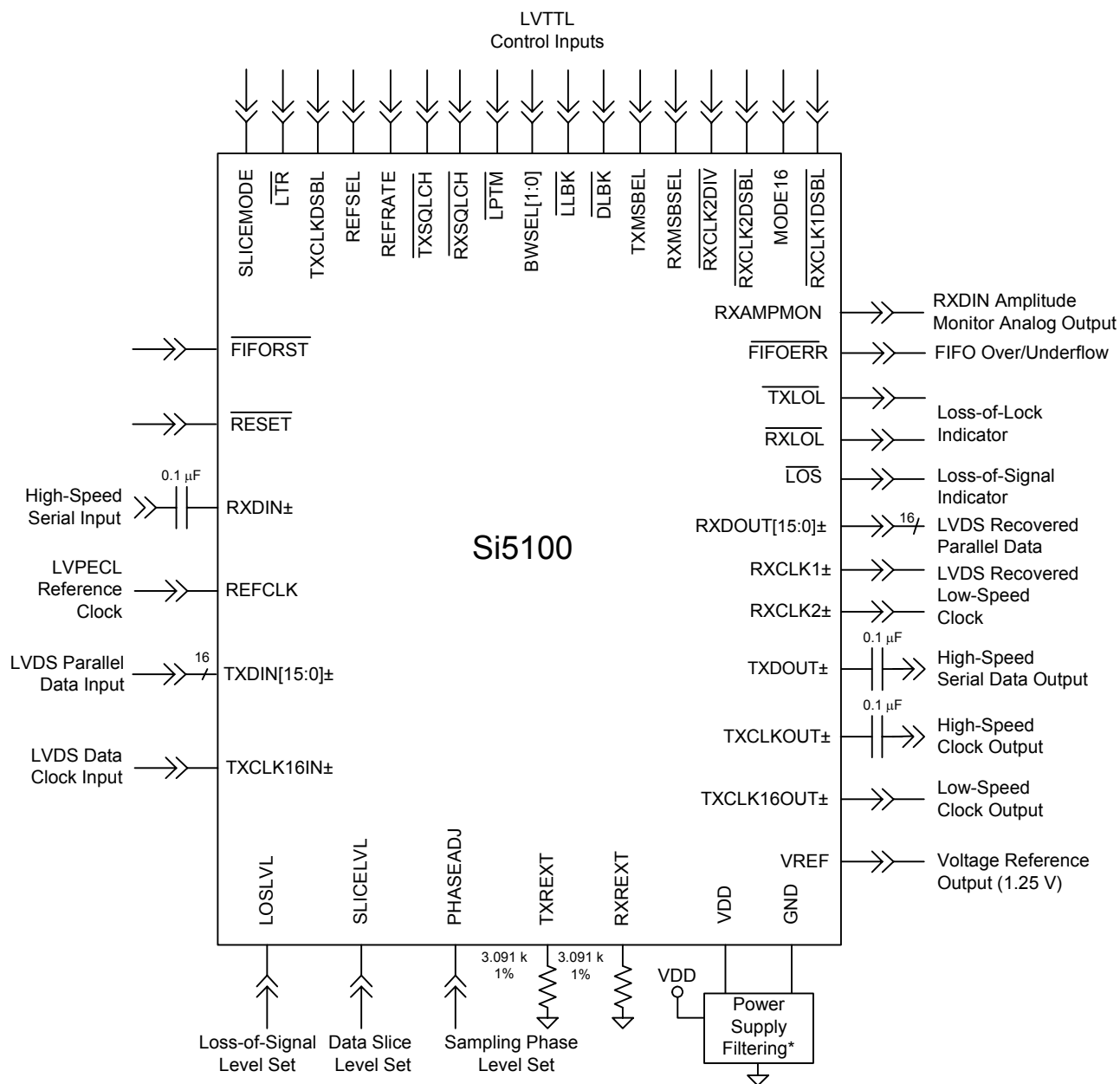
Parameter	Symbol	Value	Unit
DC Supply Voltage	V_{DD}	-0.5 to 2.2	V
LVTTTL I/O Supply Voltage	V_{DDIO}	-0.5 to 4.0	V
Differential Input Voltage (LVDS Input)	V_{DIF}	5	V
Differential Input Voltage (LVDS Output)	V_{DIF}	-0.3 to ($V_{DD} + 0.3$)	V
Differential Input Voltage (LVTTTL Input)	V_{DIF}	2.4	V
Differential Input Voltage (LVTTTL Output)	V_{DIF}	5	V
Maximum Current any output PIN		± 50	mA
Operating Junction Temperature	T_{JCT}	-55 to 150	$^{\circ}C$
Storage Temperature Range	T_{STG}	-55 to 150	$^{\circ}C$
ESD HBM (2.5 GHz Pins)		1	kV
ESD HBM Tolerance (100 pF, 1.5 k Ω)		2	kV

Note: Permanent device damage can occur if the above Absolute Maximum Ratings are exceeded. Restrict functional operation to the conditions as specified in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods might affect device reliability.

Table 8. Thermal Characteristics

Parameter	Symbol	Test Condition	Value	Unit
Thermal Resistance Junction to Ambient	φ_{JA}	Still Air	20	$^{\circ}C/W$

3. Si5100 Typical Application Schematic



Note* See "Power Supply Filtering" on page 21.

4. Functional Description

The Si5100 transceiver is a low-power fully-integrated serializer/deserializer that provides significant margin to all SONET/SDH jitter specifications. The device operates from 2.41–2.7 Gbps making it suitable for OC-48/STM-16 applications and OC-48/STM-16 applications that use 255/238 or 255/237 forward error correction (FEC) coding. The low-speed receive/transmit interface uses a low-power parallel LVDS interface compatible with LVPECL.

5. Receiver

The receiver within the Si5100 includes a precision limiting amplifier, a jitter-tolerant clock and data recovery unit (CDR), and a 1:16 demultiplexer. Programmable data slicing level and sampling phase adjustment are provided to support bit-error-rate (BER) optimization for long-haul applications.

5.1. Receiver Differential Input Circuitry

The receiver serial input provides proper termination and biasing through two resistor dividers internal to the device. The active circuitry has high-impedance inputs and provides sufficient gain for the clock and data recovery unit to recover the serial data. The input bias levels are optimized for jitter tolerance and input sensitivity and are typically not dc compatible with standard I/Os; simply ac couple the data lines as shown in Figure 10 on page 22.

5.2. Limiting Amplifier

The Si5100 incorporates a limiting amplifier with sufficient gain to directly accept the output of transimpedance amplifiers.

The limiting amplifier provides sufficient gain to fully saturate with input signals that are greater than 30 mV peak-to-peak differential. In addition, input signals up to 2 V peak-to-peak differential do not cause any performance degradation.

5.2.1. Receiver Signal Amplitude Monitoring

The Si5100 limiting amplifier includes circuitry that monitors the amplitude of the receiver differential input signal (RXDIN). The RXAMPMON output provides an analog output signal that is proportional to the input signal amplitude. The signal is enabled when slice mode is asserted. The voltage on the RXAMPMON output is nominally equal to one-half of the differential peak-to-peak signal amplitude of RXDIN as shown in Equation 1:

$$V_{\text{RXAMPMON}} \approx V_{\text{RXDIN(PP)}} \times .566$$

Equation 1

The receiver signal amplitude monitoring circuit is also used in the generation of the loss-of-signal alarm ($\overline{\text{LOS}}$).

5.2.2. Loss-of-Signal Alarm ($\overline{\text{LOS}}$)

The Si5100 can be configured to activate a loss-of-signal alarm output ($\overline{\text{LOS}}$) when the RXDIN input amplitude drops below a programmable threshold level. An appropriate level of hysteresis prevents unnecessary switching on $\overline{\text{LOS}}$.

The $\overline{\text{LOS}}$ threshold level is set by applying a dc voltage to the LOSLVL input. The mapping of the voltage on the LOSLVL pin to the $\overline{\text{LOS}}$ threshold level depends on the state of the SLICEMODE input. (The SLICEMODE input is used to select either absolute slice mode or proportional slice mode operation.)

The LOSLVL mapping for absolute slice mode (SLICEMODE = 0) is given in Figure 4. The linear region of the assert can be approximated by the following equation:

$$V_{\text{LOS}} \approx V_{\text{LOSLVL}} \times .958$$

Equation 2

where V_{LOS} is the differential PK-PK $\overline{\text{LOS}}$ threshold referred to the RXDIN input, and V_{LOSLVL} is the voltage applied to the LOSLVL pin.

The linear region of the de-assert curve can be approximated by the following equation:

$$V_{\text{LOS}} \approx V_{\text{LOSLVL}} \times .762$$

Equation 3

The LOSLVL mapping for proportional slice mode (SLICEMODE = 1) is given in Figure 6 on page 17. The linear region of the assert can be approximated by the following equation:

$$V_{\text{LOS}} \approx V_{\text{LOSLVL}} \times .61$$

Equation 4

where V_{LOS} is the differential pk-pk $\overline{\text{LOS}}$ threshold referred to the RXDIN input, and V_{LOSLVL} is the voltage applied to the LOSLVL pin.

The linear region of the de-assert curve can be approximated by the following equation:

$$V_{\text{LOS}} \approx V_{\text{LOSLVL}} \times .72$$

Equation 5

The $\overline{\text{LOS}}$ detection circuitry is disabled by tying the LOSLVL input to VREF. This forces the $\overline{\text{LOS}}$ output high.

5.2.3. Slice Level Adjustment

The limiting amplifier allows adjustment of the 0/1 decision threshold, or slice level, to allow optimization of bit-error-rates (BER) for demanding applications, such as long-haul links. The Si5100 provides two different modes of slice level adjustment: Absolute slice mode and proportional slice mode. The mode is selected using the SLICEMODE input.

In either mode, the slice level is set by applying a dc voltage to the SLICELVL input. The mapping of the voltage on the SLICELVL pin to the 0/1 decision threshold voltage (or slice voltage) depends on the selected mode of operation.

The SLICELVL mapping for absolute slice mode (SLICEMODE = 0) is given in Figure 6. The linear region of this curve can be approximated by the following equation:

$$V_{\text{LEVEL}} \approx ((V_{\text{SLICELVL}} - (V_{\text{REF}} \times 0.4)) \times 0.375) - 0.005$$

Equation 6

where V_{LEVEL} is the effective slice level referred to the RXDIN input, V_{SLICELVL} is the voltage applied to the SLICELVL pin, and V_{REF} is the reference voltage provided by the Si5100 on the VREF output pin (nominally 1.25 V).

The SLICELVL mapping for proportional slice mode (SLICEMODE = 1) is given in Figure 7 on page 18. The linear region of this curve can be approximated by the following equation:

$$V_{\text{LEVEL}} \approx [(V_{\text{SLICELVL}} - (V_{\text{REF}} \times 0.4)) \times (V_{\text{RXDIN(PP)}} \times 0.95)] - [0.03 \times V_{\text{RXDIN(PP)}}]$$

Equation 7

where V_{LEVEL} is the effective slice level referred to the RXDIN input; V_{SLICELVL} is the voltage applied to the SLICELVL pin; V_{REF} is the reference voltage provided by the Si5100 on the VREF output pin, and $V_{\text{RXDIN(PP)}}$ is the peak-to-peak voltage level of the receive data signal applied to the RXDIN input.

The slice level adjustment function can be disabled by tying the SLICELVL input the VREF. When slice level adjustment is disabled, the effective slice level is set to 0 mV relative to internally biased input common mode voltage for RXDIN.

5.3. Clock and Data Recovery (CDR)

The Si5100 uses an integrated CDR to recover clock and data from a non-return to zero (NRZ) signal input on RXDIN. The recovered clock is used to regenerate the incoming data by sampling the output of the limiting amplifier at the center of the NRZ bit period.

5.3.1. Sample Phase Adjustment

In applications where data eye distortions are introduced by the transmission medium, it may be desirable to recover data by sampling at a point that is not at the center of the data eye. The Si5100 provides a sample phase adjustment capability that allows adjustment of the CDR sampling phase across the NRZ data period. When sample phase adjustment is enabled, the sampling instant used for data recovery can be moved over a range of approximately ± 22 ps relative to the center of the incoming NRZ bit period.

The sample phase is set by applying a dc voltage to the PHASEADJ input. The mapping of the voltage present on the PHASEADJ input to the sample phase sampling offset is given in Figure 8 on page 18. The linear region of this curve can be approximated by the following equation:

$$\text{Phase Offset} \approx 85 \text{ ps/V} \times (V_{\text{PHASEADJ}} - (0.4 \times V_{\text{REF}}))$$

Equation 8

where Phase Offset is the sampling offset in picoseconds from the center of the data eye; V_{PHASEADJ} is the voltage applied to the PHASEADJ pin, and V_{REF} is the reference voltage provided by the Si5100 on the VREF output pin (nominally 1.25 V). A positive phase offset adjusts the sampling point to lead the default sampling point (the aligned center of the data eye) and a negative phase offset adjusts the sampling point to lag the default sampling point.

Data recovery using a sampling phase offset is disabled by tying the PHASEADJ input to VREF. This forces a phase offset of 0 ps to be used for data recovery.

5.3.2. Receiver Lock Detect

The Si5100 provides lock-detect circuitry that indicates whether the PLL has achieved frequency lock with the incoming data. This circuit compares the frequency of a divided down version of the recovered clock with the frequency of the supplied reference clock. The Si5100 uses either REFCLK or TXCLK16IN as the reference clock input signal depending on the state of the REFSEL input. If the (divided) recovered clock frequency deviates from that of the reference clock by more than the amount specified in Table 5 on page 10, the CDR is declared out of lock, and the loss-of-lock (RXLOL) pin is asserted. In this state, the CDR attempts to reacquire lock with the incoming data stream. During reacquisition, the recovered clock frequency (RXCLK1 and RXCLK2) drifts over a range of approximately ± 1000 ppm relative to the supplied reference clock unless LTR is asserted. The RXLOL output remains asserted until the frequency of the (divided) recovered clock differs from the reference clock frequency by less



than the amount specified in Table 5 on page 10.

The $\overline{\text{RXLOL}}$ output is asserted automatically if a valid reference clock is not detected.

The $\overline{\text{RXLOL}}$ output is also asserted whenever the loss of signal alarm ($\overline{\text{LOS}}$) is active, provided that the $\overline{\text{LTR}}$ input is set high (i.e. provided that the device is not configured for lock-to-reference mode).

5.3.3. Lock-to-Reference

The lock-to-reference ($\overline{\text{LTR}}$) input can be utilized to ensure the presence of a stable output clock during a loss-of-signal alarm ($\overline{\text{LOS}}$). When $\overline{\text{LTR}}$ is asserted, the CDR is prevented from phase locking to the data signal and the CDR locks the RXCLKOUT1 and RXCLKOUT2 outputs to the reference clock. In typical applications, the $\overline{\text{LOS}}$ output is tied to the $\overline{\text{LTR}}$ input to force a stable output clock during a loss-of-signal condition.

5.4. Deserialization

The Si5100 deserializes the high-speed data from the CDR and outputs the deserialized data on the 16-bit parallel data bus $\text{RXDOUT}[15:0]$. The demultiplexer used for deserialization is configured by the MODE16 pin to output either 4-bit or 16-bit data words on the bus. The data words are output on $\text{RXDOUT}[15:0]$ with the rising edge of RXCLK1 . When the demultiplexer is configured to output 4-bit data words, the data is output

on $\text{RXDOUT}[3:0]$.

5.4.1. Serial Input to Parallel Output Relationship

The Si5100 provides the capability to select the order in which the received serial data is mapped to the parallel output bus $\text{RXDOUT}[15:0]$. The mapping of the receive bits to the output data word is controlled by the RXMSBSEL input. When RXMSBSEL is set low, the first bit received is output on RXDOUT0 , and the following bits are output in order on RXDOUT1 through RXDOUT15 (RXDOUT1 through RXDOUT3 if $\text{MODE16} = 0$). When RXMSBSEL is set high, the first bit received is output on RXDOUT15 (RXDOUT3), and the following bits are output in order on RXDOUT14 (RXDOUT2) through RXDOUT0 .

5.5. Voltage Reference Output

The Si5100 provides an output voltage reference that can be used by external circuitry to set the $\overline{\text{LOS}}$ threshold, slicing level, or sampling phase adjustment input voltage levels. One possible implementation uses a resistor divider to set the control voltage for the LOSLVL , SLICELVL , or PHASEADJ inputs. An alternative is the use of a digital-to-analog converters (DACs) to set the control voltages. With this approach, VREF is used to set the range of the DAC outputs. The voltage on the VREF output is nominally 1.25 V.

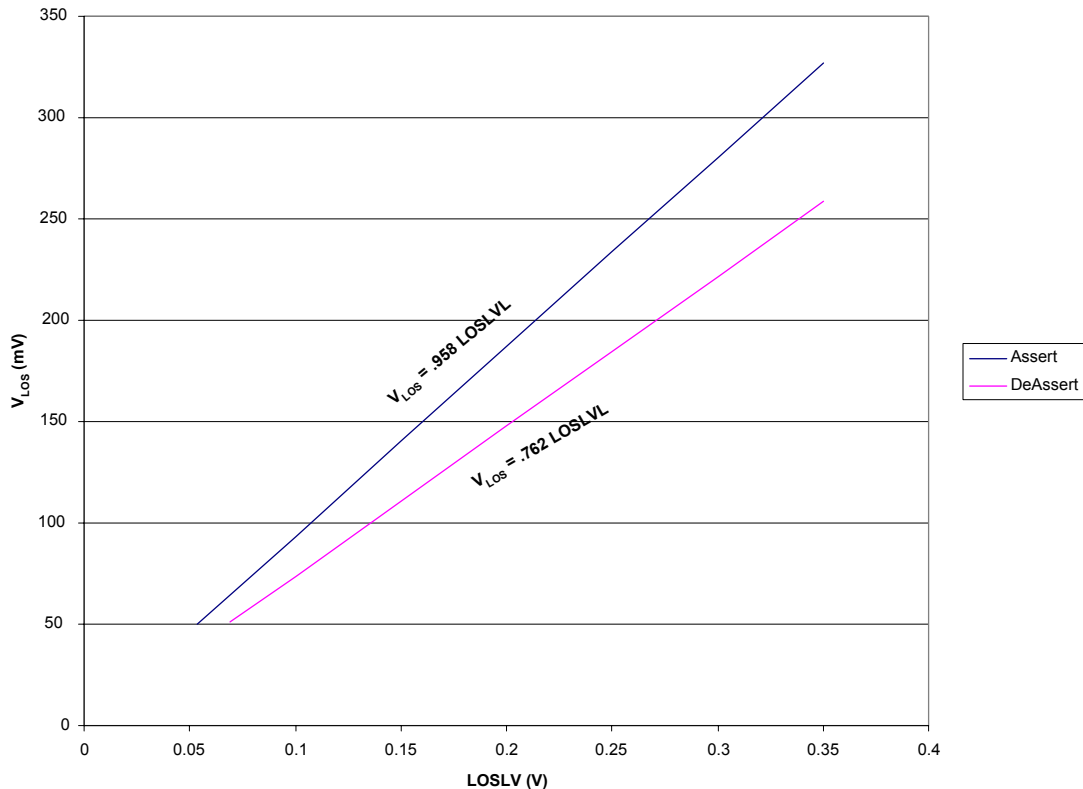


Figure 4. Typical LOSLVL Transfer Curve, Absolute Slice Mode ($\text{SLICEMODE} = 0$)

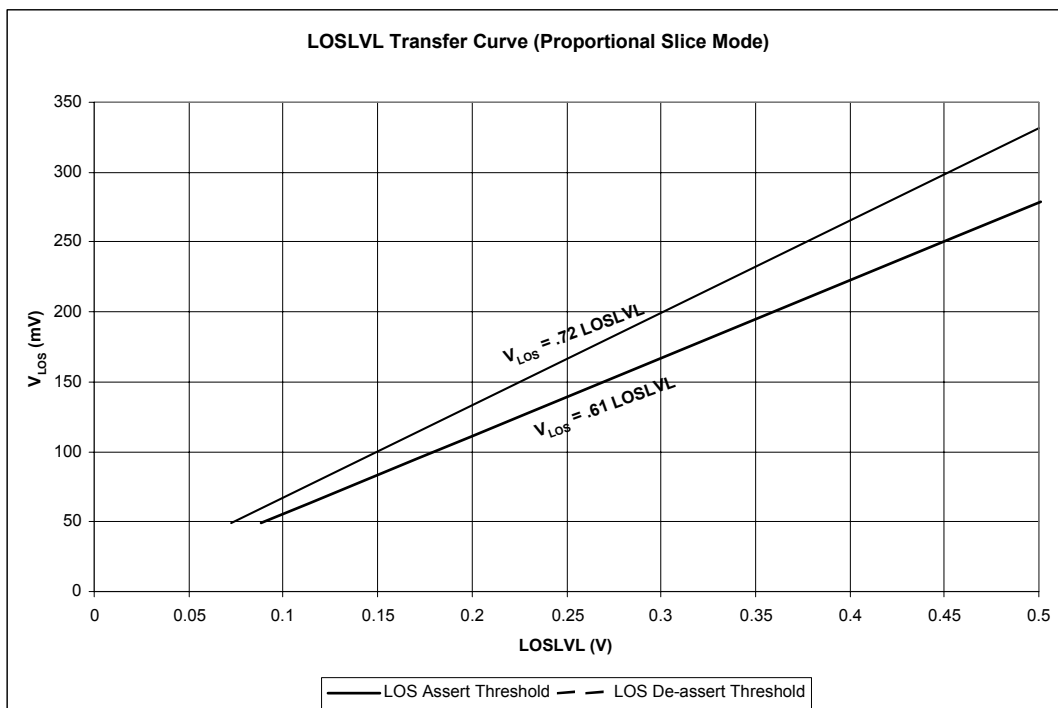


Figure 5. Typical LOSLVL Transfer Curve, Proportional Slice Mode (SLICEMODE = 1)

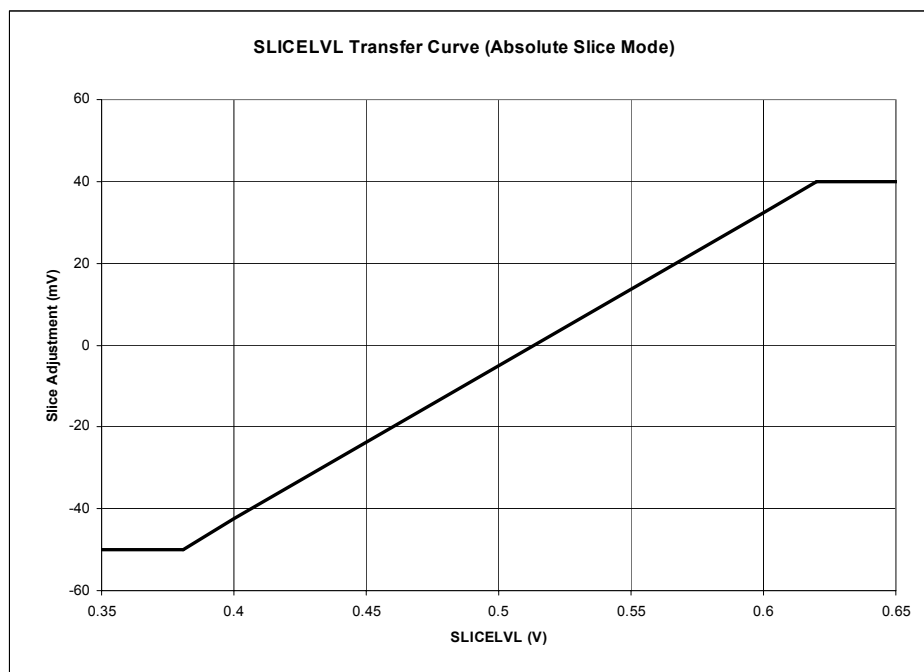


Figure 6. Typical SLICELVL Transfer Curve, Absolute Slice Mode (SLICEMODE = 0)

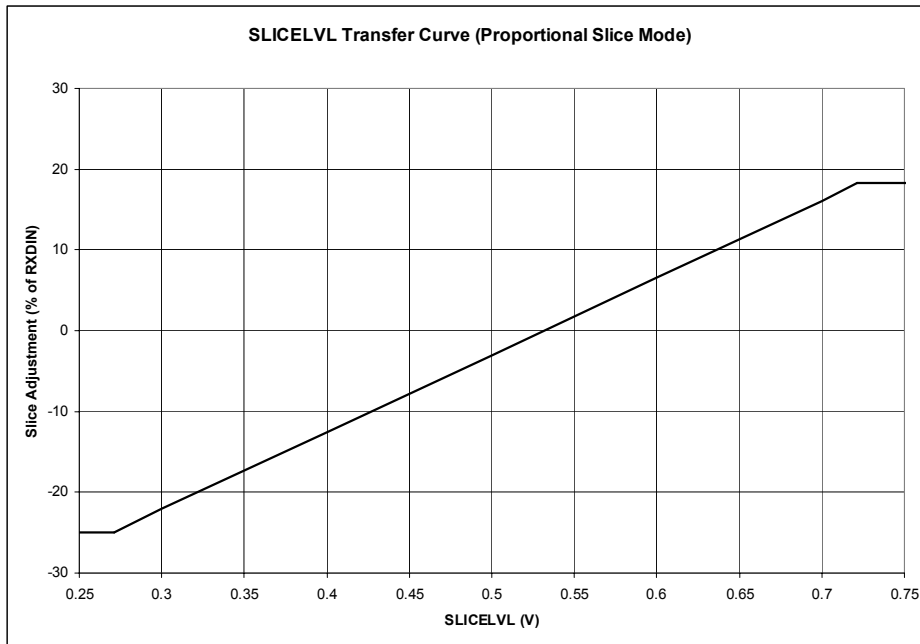


Figure 7. Typical SLICELVL Transfer Curve, Proportional Slice Mode (SLICEMODE = 1)

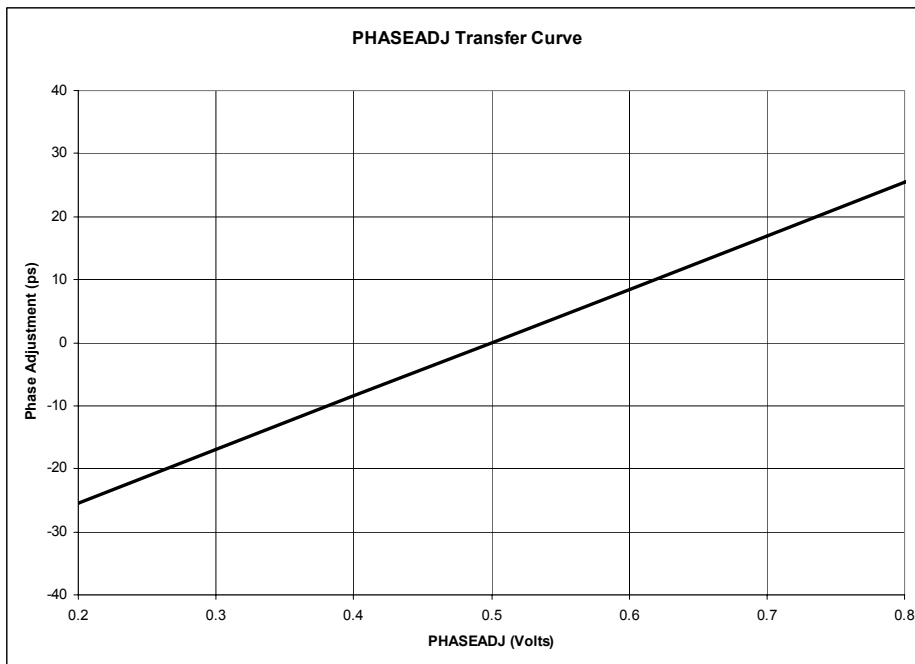


Figure 8. Typical PHASEADJ Transfer Curve

5.6. Auxiliary Clock Output

To support the widest range of system timing configurations, The Si5601/Si5602 provides a primary clock output (RXCLK1) and a secondary clock output (RXCLK2). The RXCLK2 output can be configured to provide a clock that is 1/16th or 1/64th the frequency of the high-speed recovered clock. The divide ratio which determines the RXCLK2 output frequency is selected by RXCLK2DIV.

5.7. Receive Data Squelch

During some system error conditions, such as $\overline{\text{LOS}}$, it may be desirable to force the receive data output to zero in order to avoid propagation of erroneous data into the downstream electronics. The Si5100 provides a data squelching control input, $\overline{\text{RXSQLCH}}$, for this purpose.

When the $\overline{\text{RXSQLCH}}$ input is low, the data outputs, $\overline{\text{RXDOUT}}[15:0]$, are forced to a zero state. The $\overline{\text{RXSQLCH}}$ input is ignored when the device is operating in diagnostic loopback mode ($\text{DLBK} = 0$).

6. Transmitter

The transmitter consists of a low-jitter clock multiplier unit (CMU) with a serializer that operates in either a 16:1 or 4:1 configuration. The CMU uses a phase-locked loop (PLL) architecture based on Silicon Laboratories' proprietary DSPLL technology. This technology generates low jitter clock and data outputs that provide significant margin to the SONET/SDH specifications. The DSPLL architecture also utilizes a digitally-implemented loop filter that eliminates the need for external loop filter components. As a result, sensitive noise coupling nodes that typically degrade jitter performance in crowded PCB environments are removed.

The DSPLL also reduces the complexity and relaxes the performance requirements for reference clock distribution circuitry for OC-48/STM-16 optical port cards. The DSPLL provides selectable wideband and narrowband loop filter settings that allow the jitter attenuation characteristics of the CMU to be optimized for the jitter content of the supplied reference clock. This allows the CMU to operate with reference clocks that have relatively high jitter content.

Unlike traditional analog PLL implementations, the loop filter bandwidth of the Si5100 transmitter CMU is controlled by a digital filter inside the DSPLL circuit allowing the bandwidth to be changed without changing any external component values.

6.1. DSPLL™ Clock Multiplier Unit

The Si5100's clock multiplier unit (CMU) uses Silicon Laboratories proprietary DSPLL technology to achieve optimal jitter performance. The DSPLL implementation utilizes a digital signal processing (DSP) algorithm to replace the loop filter commonly found in analog PLL designs. This algorithm processes the phase detector error term and generates a digital control value to adjust the frequency of the voltage-controlled oscillator (VCO). The DSPLL implementation requires no external loop filter components. Eliminating sensitive noise entry points makes the DSPLL implementation less susceptible to board-level noise sources and makes SONET/SDH jitter compliance easier to attain in the application.

The transmit CMU multiplies the frequency of the selected reference clock up to the serial transmit data rate. The $\overline{\text{TXLOL}}$ output signal provides an indication of the transmit CMU lock status. When the CMU has achieved lock with the selected reference, the $\overline{\text{TXLOL}}$ output is deasserted (driven high). The $\overline{\text{TXLOL}}$ signal is asserted, indicating a transmit CMU loss-of-lock condition when a valid clock signal is not detected on the selected reference clock input. The $\overline{\text{TXLOL}}$ signal is also asserted during the transmit CMU frequency calibration. Calibration is performed automatically when the Si5100 is powered on, when a valid clock signal is detected on the selected reference clock input following a period when no valid clock was present, or when the frequency of the selected reference clock is outside of the transmit CMU's PLL lock range, or after RESET is deasserted.

6.1.1. Programmable Loop Filter Bandwidth

The digitally-implemented loop filter allows for four transmit CMU loop bandwidth settings that provide wideband or narrowband jitter transfer characteristics. The filter bandwidth is selected via the $\overline{\text{BWSEL}}[1:0]$ control inputs. The loop bandwidth choices are listed in Table 6. Unlike traditional PLL implementations, changing the loop filter bandwidth of the Si5100 is accomplished without the need to change external component values.

Lower loop bandwidth settings (Narrowband operation) make the Si5100 more tolerant to jitter on the reference clock source. As a result, circuitry used to generate and distribute the physical layer reference clocks can be simplified without compromising margin to the SONET/SDH jitter specifications.

Higher loop bandwidth settings (Wideband operation) are useful in applications where the reference clock is provided by a low jitter source, such as the Si5364 Clock Synchronization IC or Si5320 Precision Clock

Multiplier/Jitter Attenuator IC. Wideband operation allows the DSPLL to more closely track the precision reference source resulting in the best possible jitter performance.

6.2. Serialization

The Si5100 serialization circuitry is comprised of a FIFO and a parallel to serial shift register. The device can be configured to serialize either 4-bit data words input on TXDIN[3:0] or 16-bit data words input on TXDIN[15:0]. The 4-bit or 16-bit configuration is selected using the MODE16 input. Low-speed data on the parallel input bus is latched into the FIFO on the rising edge of TXCLK16IN. Data is clocked out of the FIFO and into the shift register by TXCLK16OUT. The high-speed serial data stream TXDOUT is clocked out of the shift register by TXCLKOUT. The TXCLK16OUT clock is provided as an output signal to support either 4-bit or 16-bit word transfers between the Si5100 and upstream devices using a counter clocking scheme.

6.2.1. Input FIFO

The Si5100 transmit FIFO decouples the timing of the data transferred into the FIFO via TXCLK16IN from the data transferred into the shift register via TXCLK16OUT. The FIFO is eight parallel words deep and accommodates static phase delay that may be introduced between TXCLK16OUT and TXCLK16IN in counter clocking schemes. Furthermore, the FIFO accommodates a bounded phase drift, or wander, between TXCLK16IN and TXCLK16OUT of up to three parallel data words.

The FIFO circuitry indicates an overflow or underflow condition by asserting the FIFOERR signal. This output can be used to re-center the FIFO read/write pointers by tying it directly to the FIFORST input.

The FIFORST signal causes re-centering of the FIFO read/write pointers. The Si5100 also automatically re-centers the read/write pointers after the device is powered on, after an external reset via the RESET input, and each time the DSPLL transitions from an out-of-lock state to a locked state (when TXLOL transitions from low to high).

6.2.2. Parallel Input To Serial Output Relationship

The Si5100 provides the capability to select the order in which the data received on the parallel input bus, TXDIN[15:0], is transmitted serially on the high-speed serial data output, TXDOUT. Data on the parallel bus is transmitted MSB first or LSB first depending on the setting of the TXMSBSEL input. When TXMSBSEL is set low, TXDIN0 is transmitted first, followed in order by TXDIN1 through TXDIN15 (TXDIN1 through TXDIN3 if MODE16 = 0). When TXMSBSEL is set high, TXDIN15

(TXDIN3) is transmitted first, followed in order by TXDIN14 (TXDIN2) through TXDIN0. This feature can simplify printed circuit board (PCB) routing in applications where ICs are mounted on both sides of the PCB.

6.2.3. Transmit Data Squelch

To prevent the transmission of corrupted data into the network, the Si5100 provides a control pin that can be used to force the high-speed serial data output TXDOUT to zero. When the TXSQLCH input is set low, the TXDOUT signal is forced to a zero state. The TXSQLCH input is ignored when the device is in line loopback mode ($\overline{\text{LLBK}} = 0$).

6.2.4. Clock Disable

The Si5100 provides a clock disable pin, TXCLKDSBL, that can be used to disable the high-speed serial data clock output, TXCLKOUT. When the TXCLKDSBL pin is asserted, the positive and negative terminals of CLKOUT are internally tied to 1.5 V through 50 Ω on-chip resistors.

This feature can be used to reduce power consumption in applications that do not use the high-speed transmit data clock.

7. Loop Timed Operation

The Si5100 can be configured to provide SONET/SDH compliant loop timed operation. When the LPTM input is set low, the transmit clock and data timing is derived from the CDR recovered clock output. This is achieved by dividing down the recovered clock and using it as a reference source for the transmit CMU. This results in transmit clock and data signals that are locked to the timing recovered from the received data path. A narrow-band loop filter setting is recommended for this mode of operation.

8. Diagnostic Loopback

The Si5100 provides a diagnostic loopback mode that establishes a loopback path from the serializer output to the deserializer input. This provides a mechanism for looping back data input via the low-speed transmit interface, TXDIN[15:0], to the low-speed receive data interface, RXDOUT[15:0]. This mode is enabled when the DLBK input is set low.

Note: Setting both $\overline{\text{DLBK}}$ and $\overline{\text{LLBK}}$ low simultaneously is not supported.

9. Line Loopback

The Si5100 provides a line loopback mode that establishes a loopback path from the high-speed receive input to the high-speed transmit output. This provides a mechanism for looping back the high-speed clock and data recovered from RXDIN to the transmit data output, TXDOUT, and clock, TXCLKOUT. This mode is enabled when the $\overline{\text{LLBK}}$ input is set low.

Note: Setting both $\overline{\text{DLBK}}$ and $\overline{\text{LLBK}}$ low simultaneously is not supported.

10. Bias Generation Circuitry

The Si5100 uses two external resistors, RXREXT and TXREXT, to set internal bias currents for the receive and transmit sections of the device, respectively. The external resistors allow precise generation of bias currents, which can significantly reduce power consumption. The bias generation circuitry requires two 3.09 k Ω (1%) resistors each connected between RXREXT and GND and between TXREXT and GND.

11. Reference Clock

The Si5100 supports operation with one of two possible reference clock sources. In the first configuration, an external reference clock is connected to the REFCLK input. The second configuration uses the parallel data clock, TXCLK16IN, as the reference clock source. The REFSEL input is used to select whether the REFCLK or the TXCLK16IN input are used as the reference clock.

When REFCLK is selected as the reference clock source (REFSEL = 1), two possible reference clock frequencies are supported. The reference clock frequency provided on the REFCLK input can be either 1/16th or 1/32th the desired transceiver data rate. The REFCLK frequency is selected using the REFRATE input.

The TXCLK16IN clock frequency is equal to either 1/4th or 1/16th the transceiver data rate depending on the state of the MODE16 input. When TXCLK16IN is selected as the reference clock source (REFSEL = 0), the REFRATE input has no effect.

The CMU in the Si5100's transmit section multiplies the provided reference up to the serial transmit data rate. When the CMU has achieved lock with the selected reference, the TXLOL output is deasserted (driven high).

The CDR in the receive section of the Si5100 uses the selected reference clock to center the receiver PLL frequency in order to speed lock acquisition. When the receive CDR locks to the data input, the RXLOL signal is deasserted (driven high).

12. Reset

The Si5100 is reset by holding the $\overline{\text{RESET}}$ pin low for at least 1 μs . When $\overline{\text{RESET}}$ is asserted, the input FIFO pointers are reset and the digital control circuitry is initialized.

When $\overline{\text{RESET}}$ transitions high to start normal operation, the transmit CMU calibration is performed.

13. Transmit Differential Output Circuitry

The Si5100 utilizes a current-mode logic (CML) architecture to drive the high-speed serial output clock and data on TXCLKOUT and TXDOUT. An example of output termination with ac coupling is shown in Figure 9. In applications with direct dc coupling, the 0.1 μF capacitors can be omitted. The differential peak-to-peak voltage swing of the CML architecture is listed in Table 2.

14. Internal Pullups and Pulldowns

On-chip 30 k Ω resistors are used to individually set the LVTTTL inputs if these inputs are left unconnected. The specific default state of each input is enumerated in "Pin Descriptions: Si5100" on page 26.

15. Power Supply Filtering

The transmitter-generated jitter is most sensitive to power supply noise below its PLL loop-bandwidth (BWSEL setting). The power supply noise of interest is bounded between the SONET/SDH generated jitter specification of 12 kHz (for 2.48832 Gbps) and the PLL loop-bandwidth. Integrated supply noise from 1/10th the SONET/SDH specification (1.2 kHz) to 10x the loop-bandwidth should be suppressed to a level appropriate for each design. Below the PLL loop-bandwidth, the typical generated jitter due to supply noise is approximately 2.5 mUIpp per 1 mVrms; this parameter can be used as a guideline for calculating the output jitter and supply filtering requirements. The receiver does not place additional power supply constraints beyond those listed for the transmitter.

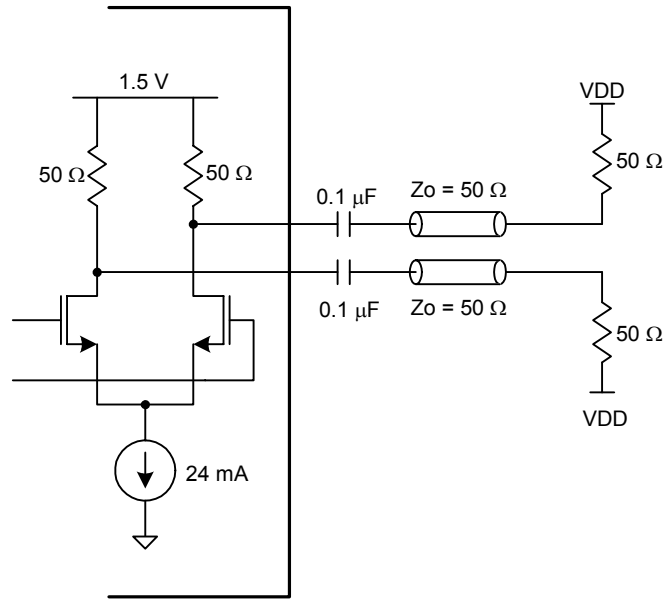


Figure 9. CML Output Driver Termination (TXCLKOUT, TXDOUT)

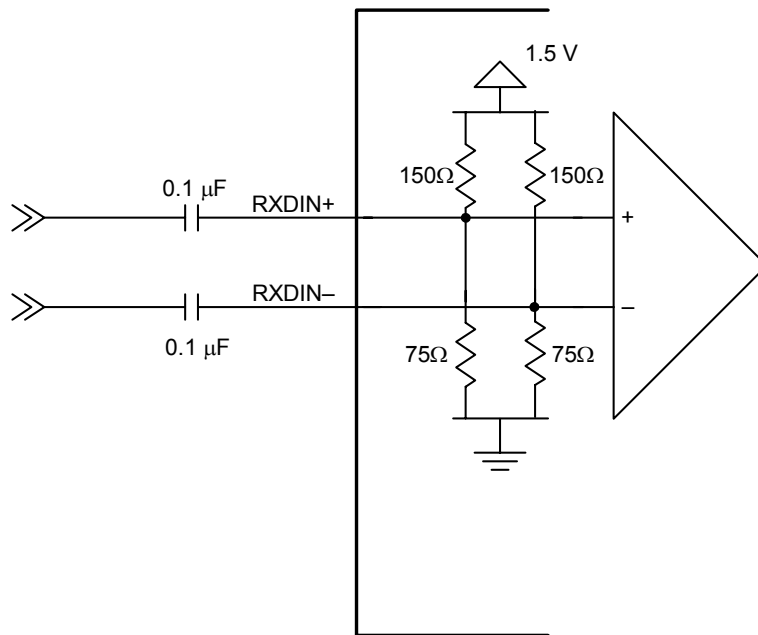


Figure 10. Receiver Differential Input Circuitry

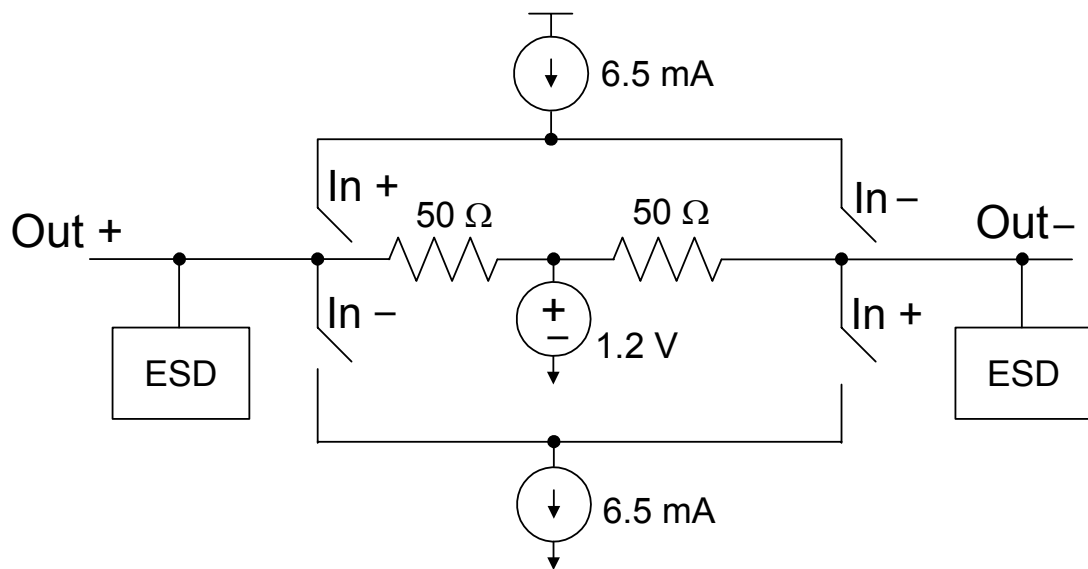


Figure 11. LVDS Driver Termination (RXDOUT, TXCLK16OUT)

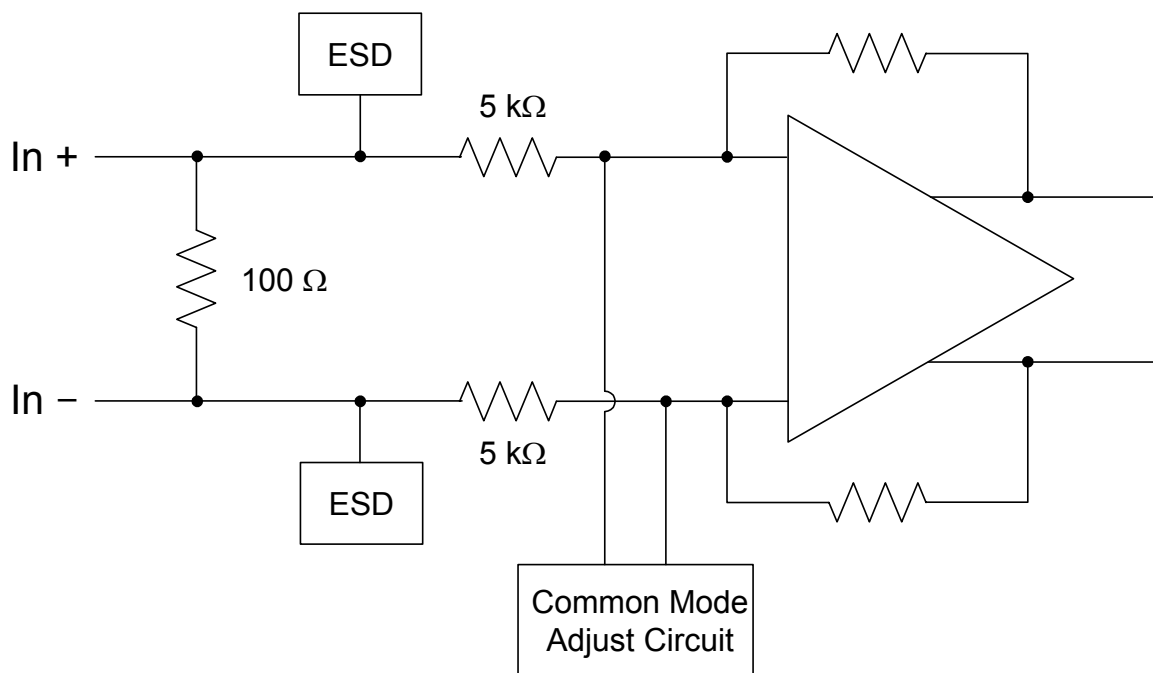


Figure 12. LVDS Differential Input Circuitry

16. Si5100 Pinout: 195 BGA

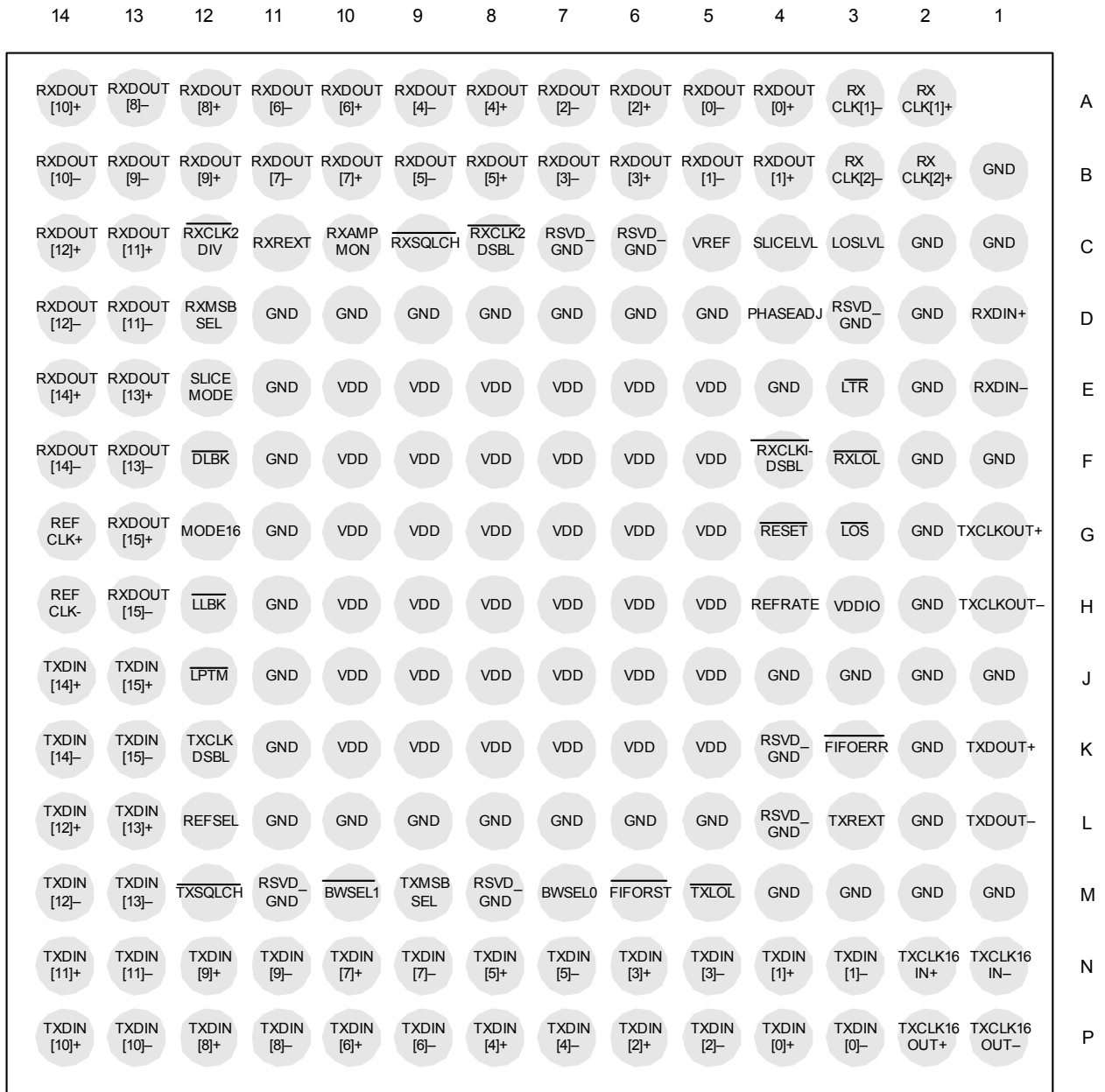


Figure 13. Si5100 Pin Configuration (Bottom View)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14
A		RX CLK[1]+	RX CLK[1]-	RXDOUT [0]+	RXDOUT [0]-	RXDOUT [2]+	RXDOUT [2]-	RXDOUT [4]+	RXDOUT [4]-	RXDOUT [6]+	RXDOUT [6]-	RXDOUT [8]+	RXDOUT [8]-	RXDOUT [10]+
B	GND	RX CLK[2]+	RX CLK[2]-	RXDOUT [1]+	RXDOUT [1]-	RXDOUT [3]+	RXDOUT [3]-	RXDOUT [5]+	RXDOUT [5]-	RXDOUT [7]+	RXDOUT [7]-	RXDOUT [9]+	RXDOUT [9]-	RXDOUT [10]-
C	GND	GND	LOSLVL	SLICELVL	VREF	RSVD_GND	RSVD_GND	RXCLK2 DSBL	RXSQLCH	RXAMP MON	RXREXT	RXCLK2 DIV	RXDOUT [11]+	RXDOUT [12]+
D	RXDIN+	GND	RSVD_GND	PHASE ADJ	GND	GND	GND	GND	GND	GND	GND	RXMSB SEL	RXDOUT [11]-	RXDOUT [12]-
E	RXDIN-	GND	LTR	GND	VDD	VDD	VDD	VDD	VDD	VDD	GND	SLICE MODE	RXDOUT [13]+	RXDOUT [14]+
F	GND	GND	RXL0L	RXCLK1 DSBL	VDD	VDD	VDD	VDD	VDD	VDD	GND	DLBK	RXDOUT [13]-	RXDOUT [14]-
G	TXCLKOUT+	GND	LOS	RESET	VDD	VDD	VDD	VDD	VDD	VDD	GND	MODE16	RXDOUT [15]+	REF CLK+
H	TXCLKOUT-	GND	VDDIO	REFRATE	VDD	VDD	VDD	VDD	VDD	VDD	GND	LLBK	RXDOUT [15]-	REF CLK-
J	GND	GND	GND	GND	VDD	VDD	VDD	VDD	VDD	VDD	GND	LPTM	TXDIN [15]+	TXDIN [14]+
K	TXDOUT+	GND	FIFOERR	RSVD_GND	VDD	VDD	VDD	VDD	VDD	VDD	GND	TXCLK DSBL	TXDIN [15]-	TXDIN [14]-
L	TXDOUT-	GND	TXREXT	RSVD_GND	GND	GND	GND	GND	GND	GND	GND	REFSEL	TXDIN [13]+	TXDIN [12]+
M	GND	GND	GND	GND	TXL0L	FIFORST	BWSEL0	RSVD_GND	TXMSB SEL	BWSEL1	RSVD_GND	TXSQLCH	TXDIN [13]-	TXDIN [12]-
N	TXCLK16 IN-	TXCLK16 IN+	TXDIN [1]-	TXDIN [1]+	TXDIN [3]-	TXDIN [3]+	TXDIN [5]-	TXDIN [5]+	TXDIN [7]-	TXDIN [7]+	TXDIN [9]-	TXDIN [9]+	TXDIN [11]-	TXDIN [11]+
P	TXCLK16 OUT-	TXCLK16 OUT+	TXDIN [0]-	TXDIN [0]+	TXDIN [2]-	TXDIN [2]+	TXDIN [4]-	TXDIN [4]+	TXDIN [6]-	TXDIN [6]+	TXDIN [8]-	TXDIN [8]+	TXDIN [10]-	TXDIN [10]+

Figure 14. Si5100 Pin Configuration (Transparent Top View)